# Application/Control No. 10/044,904

Applicant(s)/Patent Under Reexamination HEDEN ET AL.

Examiner

Karin M. Reichle

Art Unit 3761

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## Notice of References Cited

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,776,234	12-1973	Hoey, Raymond M.	604/390
	В	US-4,100,921	07-1978	Schaar, Charles H.	604/390
	C	US-6,494,873	12-2002	Karlsson et al.	604/392
	D	US-6,648,871	11-2003	Kusibojoska et al.	604/392
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	7	US-			
	К	US-			
	L	US-			
	М	US-			

#### **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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#### NON-PATENT DOCUMENTS

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ſ	*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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